

INFORMATION DISCLOSURE CITATION <i>(Use several sheets if necessary)</i>			ATTY DOCKET NO. BUR920020008US		SERIAL NO. 10/063,406		
			Breitwisch et al.		FILING GROUP 4/19/2002 2822		
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
<i>JH/S</i>		4,558,508	12/17/85	Kinney et al.	29	571	10/15/84
		4,613,885	09/23/86	Haken	357	42	01/12/84
		4,929,565	05/29/90	Parrillo	437	34	10/30/89
		5,138,420	08/11/92	Komori et al.	357	42	10/31/90
		5,304,833	04/19/94	Shigeki et al.	257	372	09/10/90
		5,384,279	01/24/95	Stolmeijer et al.	437	57	10/27/93
		5,494,843	02/27/96	Huang	437	56	06/28/95
		5,792,680	08/11/98	Sung et al.	438	210	11/25/96
		5,814,866	09/29/98	Borland	257	369	03/18/96
		5,963,799	10/05/99	Wu	438	199	03/23/98
		6,144,076	11/07/00	Puchner et al.	257	369	12/08/98
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION
							YES
OTHER DOCUMENTS <i>(Including Author, Title, Date, Pertinent Pages, Etc.)</i>							
<i>W. S. Johnson, "Multiple Masking Technique In Ion Implantation", IBM TDB Vol. 15, No. 2 July 1972, pp. 660-661</i>							
EXAMINER				DATE CONSIDERED	<i>6/26/05</i>		

**\*EXAMINER:** Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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